

Manufacturing Technology for Platinum Resistance Temperature Detectors

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Temperature Sensors

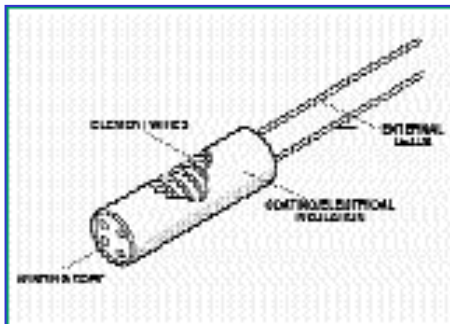
- **Non-contact type**
 - Radiation temperature detector
 - Optical pyrometer
- **Contact type**
 - Thermistor
 - Resistance temperature detectors(RTD)
 - Thermocouple

Characterization of contact type temperature sensors

	RTD (Platinum RTD)	Thermocouple	Thermistor
Temperature Range	-200°C ~ 850°C	-190°C ~ 1821°C	0 °C ~ 300 °C
Accuracy	±0.001°F to 0.1°F	±1°F to 10°F	High
Response Time	Moderate	Fast	Fast
Stability	Excellent long-term stability	Poor stability	Good stability
Linearity	Best	Moderate	Non-linear
Sensitivity	High sensitivity	Low sensitivity	High sensitivity

Platinum RTD

Wire type



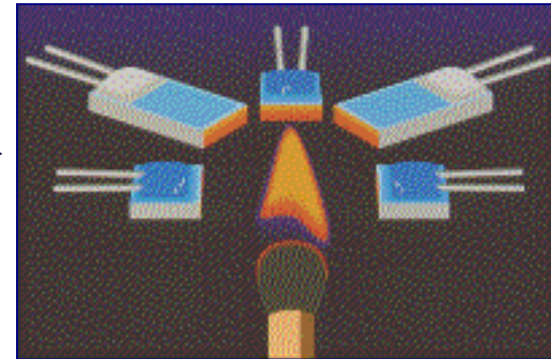
- standard PRTD
- accuracy
- high cost

Ceramic capsule type



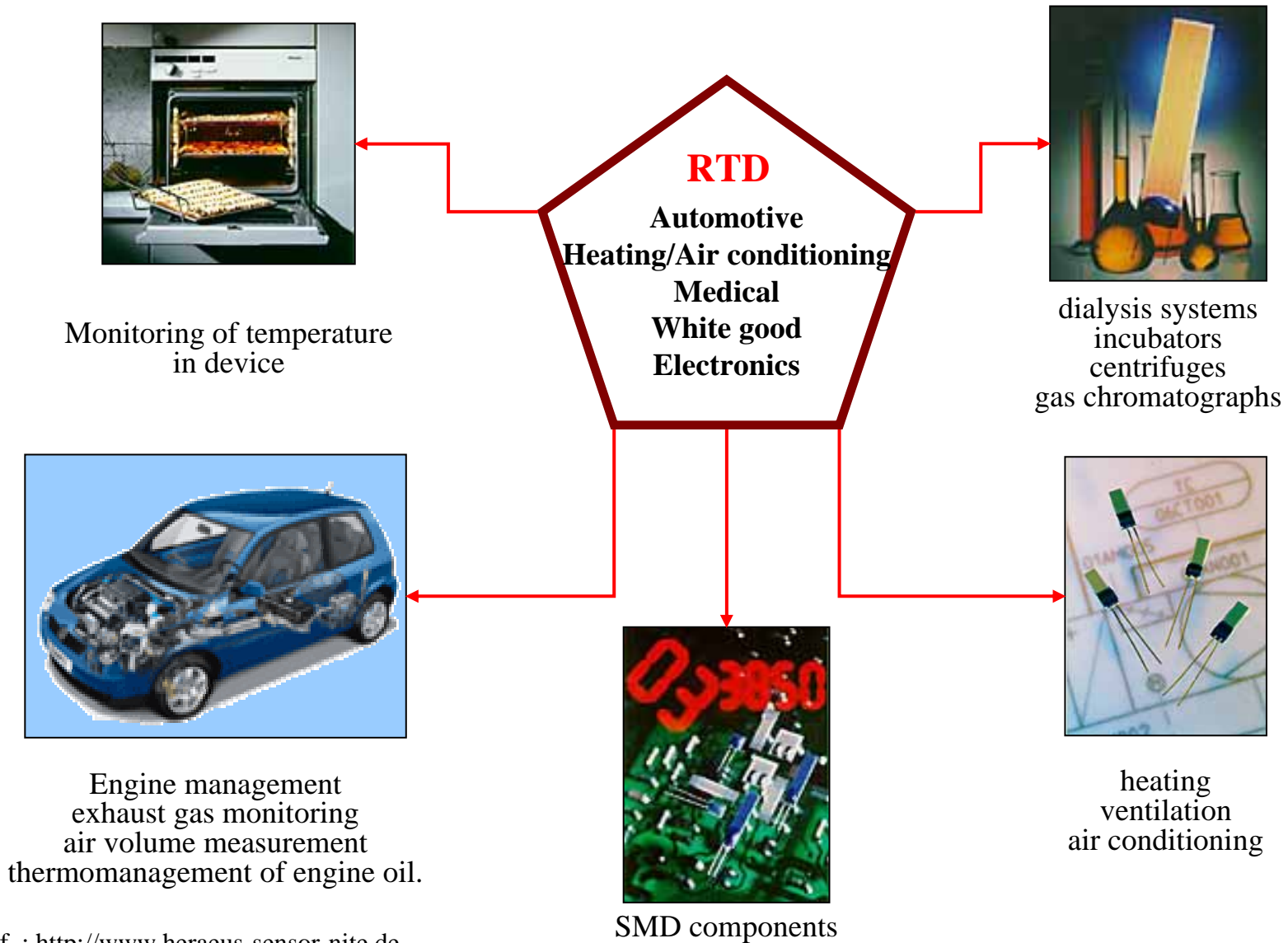
- high endurance
- high cost
- late response

Thin film type



- moderate response
- small size
- good reproducibility
- good long-term stability
- low cost

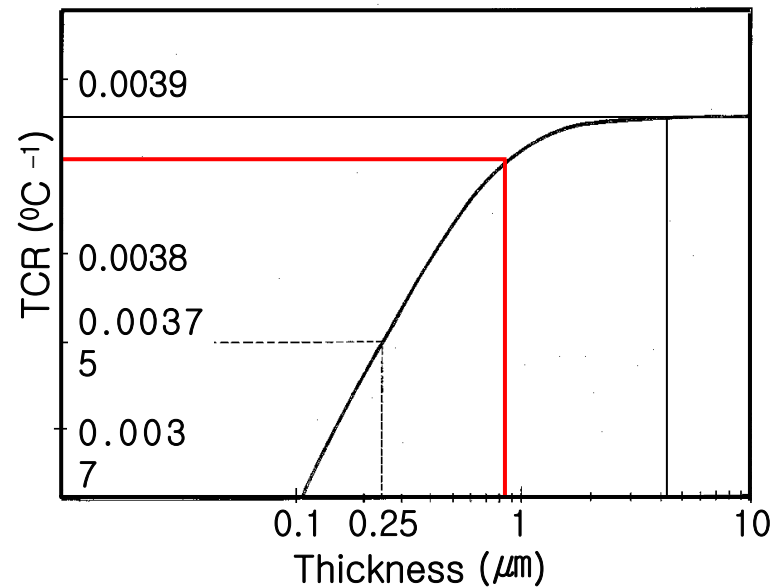
Applications of Platinum RTD*



* Ref. : <http://www.heraeus-sensor-nite.de>

TCR vs. Platinum film thickness

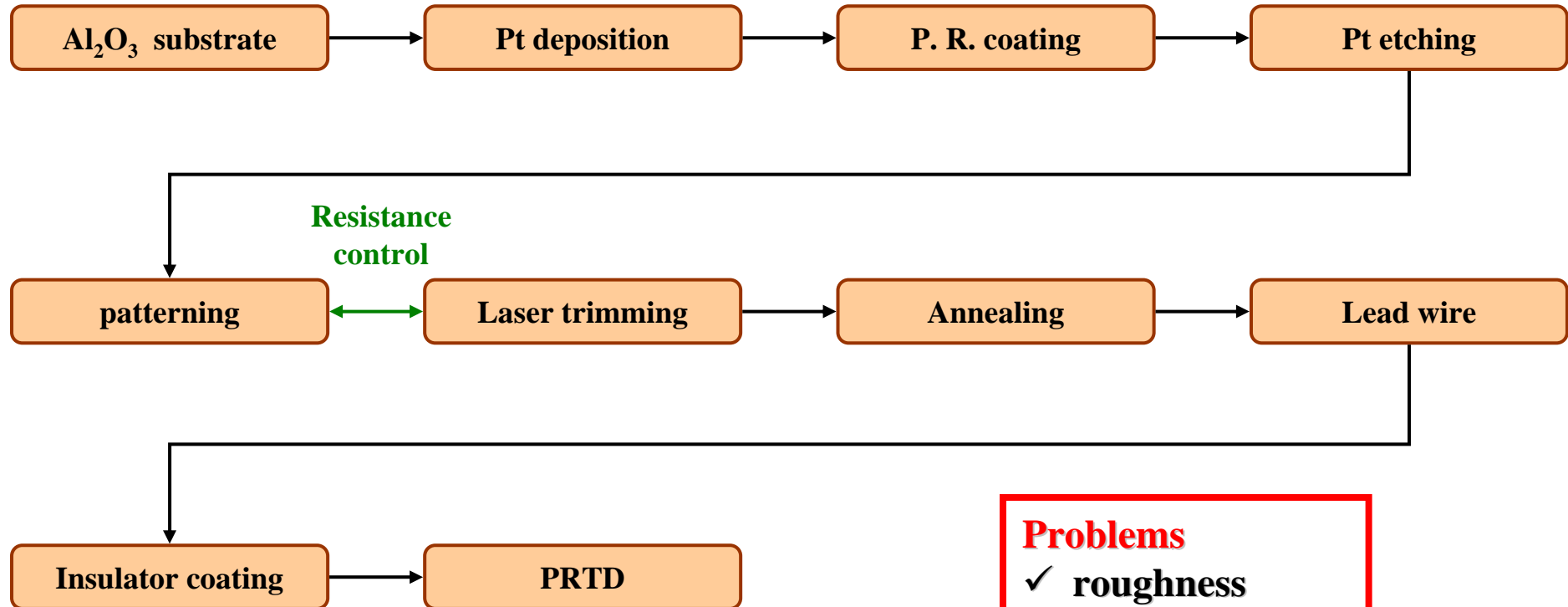
**For realization of platinum resistance temperature detectors,
effective film thickness is required (see red line)**



Pt TCR values as a function of film thickness*

* ref. : R. D. Baxter, P. J. Freud, US Patent, 4375056 (1983)

Conventional Pt-RTD process (Commercial products)

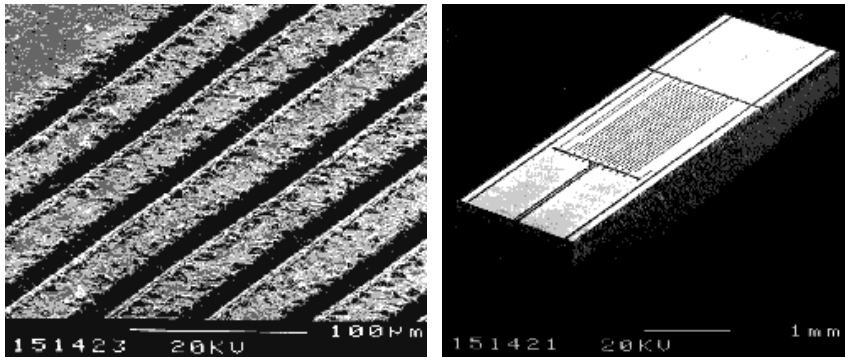


Problems

- ✓ roughness
- ✓ response time
- ✓ Pt etchability
- ✓ laser trimming
- ✓ cost

Conventional patterning process (commercial products)

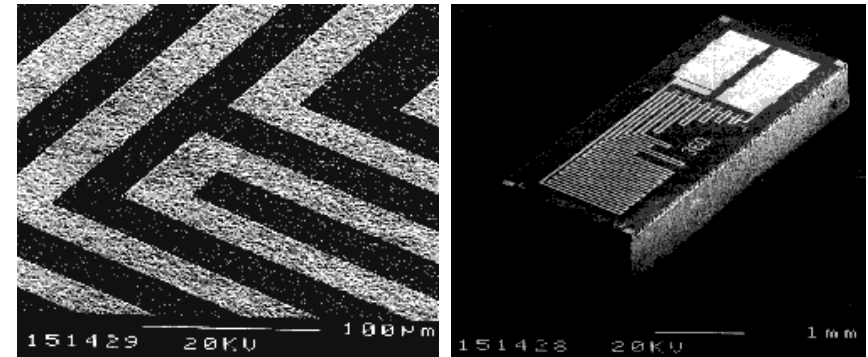
Laser trimming



Disadvantages

- Degradation of Pt film
- Limitation of line width to the laser beam size
- Low yield

Photolithography



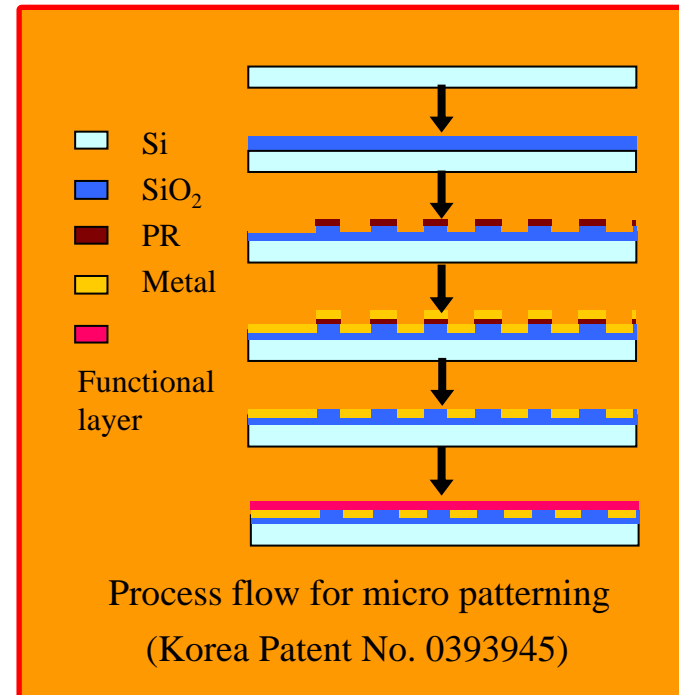
Disadvantages

- Trimming pattern is necessary
- Etchability of Pt is not good.

Embedded patterning

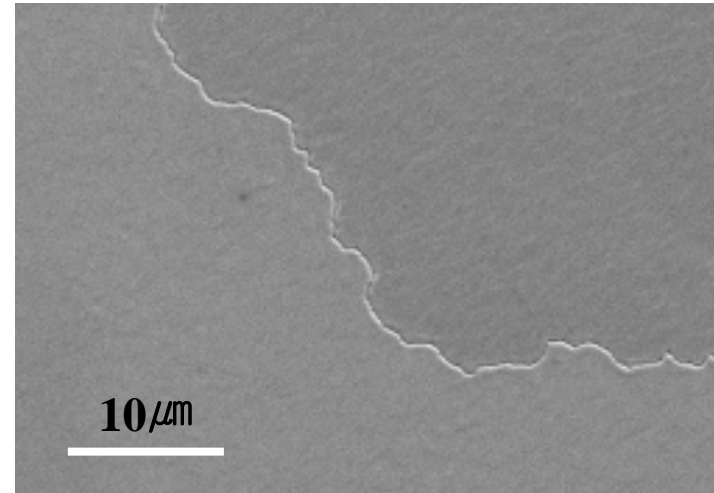
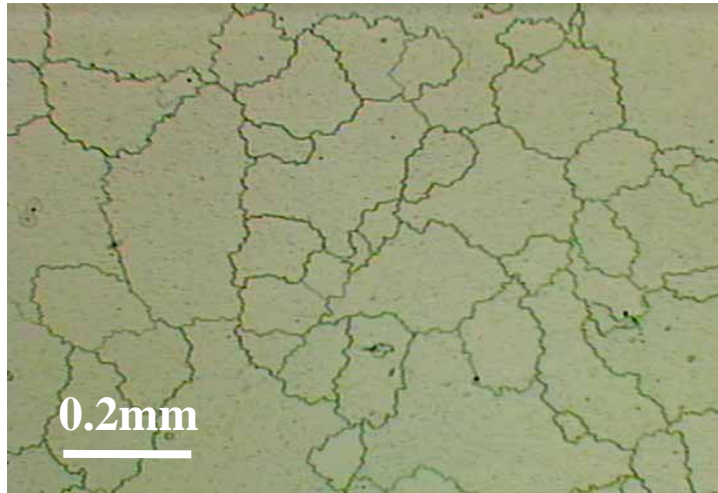
Feature of INOSTEK's Micro-patterning Technology

- Embedded pattern
- No needs for planization
- Compatibility with other processes
- High yield



Giant grained Pt films

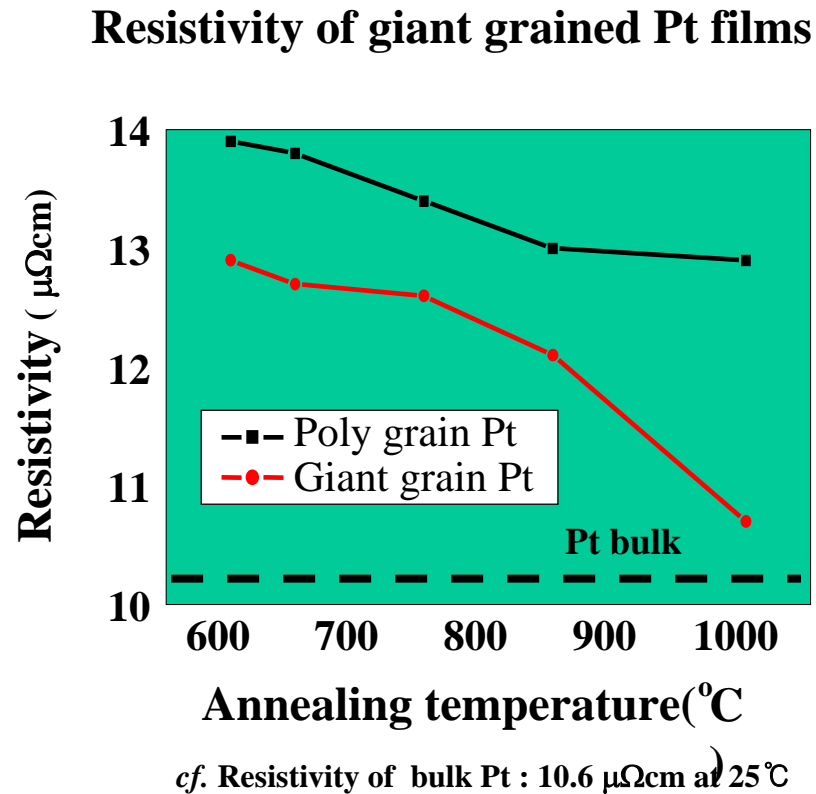
❖ Giant grained Pt films are used as sensing materials



- Giant grained Pt film consisting of cm-ordered grains can be made by sputtering with Ar+O₂ gas mixture.
- The preferred orientation of giant grained Pt can be controlled.
- After annealing, deposited Pt film completely transforms to giant grain.
- The resistivity of giant grained Pt is lower than that of normal grained Pt.

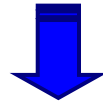
Giant grained Pt films

The **resistivity** of giant grained Pt was lower than normal grained Pt.



INOSTEK's Platinum RTD sensor

Using Si wafer substrates



Device Spec.	unit	World best spec.	R&D spec. in KOREA	INOSTEK spec.
TCR ¹⁾	1/°C	0.00385	0.0038	0.00385
Standard Resis. ²⁾	Ω	100 ~ 10000	100	100 ~ 10000
Line width	μm	10		10
Dimension ³⁾	mm ²	1x1	5x5	2x2
Tolerances	°C	±(0.15 + 0.002*t)		± (0.15 + 0.002*t)

¹⁾ TCR: temperature coefficient of resistance

$$\alpha = (R_{100} - R_0) / (100 * R_0) \text{ in } /^{\circ}\text{C}$$

R_{100} : resistance at 100°C , R_0 : resistance at 0°C

²⁾ Standard resistance: resistance at 0°C (R_0)

Sensitivity ($\Delta R/\Delta T$) depends on R_0

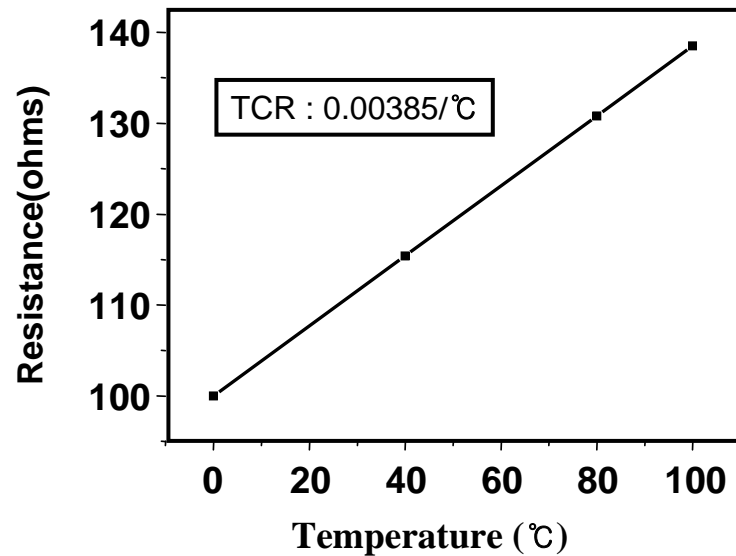
³⁾ Dimension : response time, self-heating error

Characteristics of INOSTEK's Pt RTD sensor

TCR depends on

- ✓ purity
- ✓ thermal mismatch between substrate and platinum film
- ✓ annealing temperature

TCR measurement



TCR: temperature coefficient of resistance

$$\alpha = (R_{100} - R_0) / (100 * R_0) \text{ in } /^\circ\text{C}$$

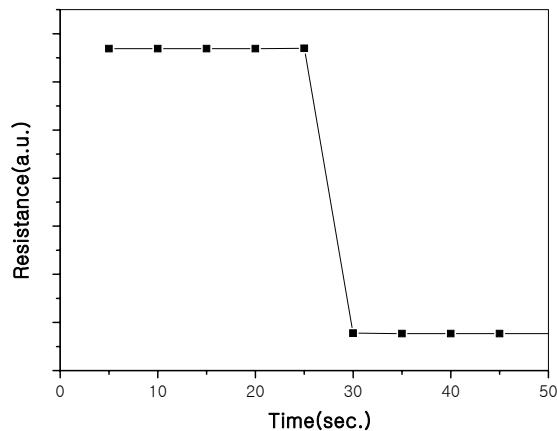
R_{100} : resistance at 100 °C , R_0 : resistance at 0 °C

Characteristics of INOSTEK's Pt RTD sensor

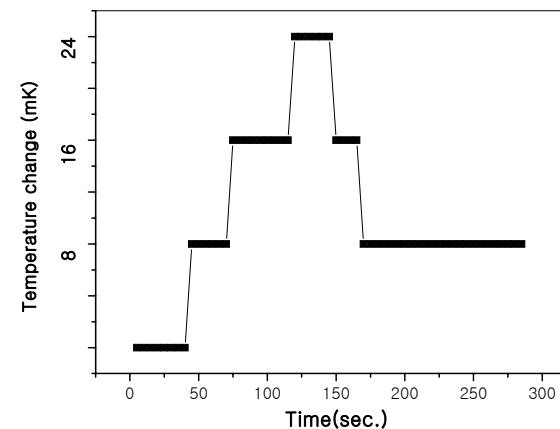
❖ *Fast response* due to the high thermal conductivity of Si wafer

6 times $\left\{ \begin{array}{l} \checkmark \text{Al}_2\text{O}_3 : 25 \text{ W/mK} \\ \checkmark \text{Si wafer} : 148 \text{ W/mK} \end{array} \right.$

Measurement of time constant
(from 25 °C to ice point)



Self heating effects



Self heating caused by measuring current could be reduced by fast heat transfer.
Thus, Si wafer is more useful than alumina as a substrate.

INOSTEK's Platinum RTD sensor and RTD wafer

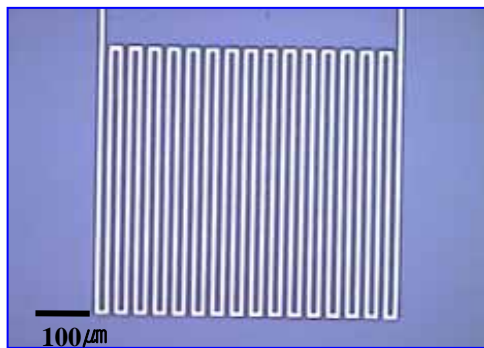
- Based on silicon wafer
- Microstructure control of platinum
(Single crystal Pt film)
- Unique patterning method

INOSTEK's Technology



6 inch platinum RTD wafer

provides



Platinum RTD

TCR : 0.00385 R_0 : 100, 1000, 10000 Ω

Advantages

- Fast response
- Enhanced electrical properties
- Small sensing area
- Unlimited measuring points
- High accuracy by high standard resistance